AF/2863 RFW

Attorney Docket No.: CRDC-P0363

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent

In re Application of:

Inventor(s): Burnell G. West

Application No.: 10/056,287 Examiner:

Filed: 01/23/02 Art Unit:

For: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT SYSTEM

Patent No.: Issued Date:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

POWER OF ATTORNEY BY ASSIGNEE OF ENTIRE INTEREST (REVOCATION OF PRIOR POWERS)

As assignee of record of the entire interest of the above identified
[X] application,
[ ] patent,

REVOCATION OF PRIOR POWERS OF ATTORNEY

[X] I hereby revoke all previous powers of attorney given in the above-identified application/patent.

NEW POWER OF ATTORNEY

[X] I hereby appoint the practitioners associated with the customer Number: **45595**

[X] Please change the correspondence address for the above-identified application to:
The address associated with Customer Number: : **45595**

I am the:
[X] Assignee of record of the entire interest. *Statement under 37 CFR 3.73(b) is below.*

CERTIFICATE UNDER 37 CFR 3.73(b)

CREDENCE SYSTEMS CORPORATION., a California corporation, certifies that it is the assignee of the entire right, title and interest in the patent identified above by virtue of:

[ ] An assignment from the inventor(s) of the patent application/patent identified above. The assignment was recorded in The United States Patent and Trademark Office at
Reel _____. Frame _____.

[X] Copies of assignments or other documents in the chain of title are attached.

The undersigned has reviewed all the documents in the chain of title of the patent application/patent identified above and, to the best of undersigned's knowledge and belief, title is in the assignee identified above.

The undersigned (whose title is supplied below) avers that the undersigned is empowered to sign this certificate on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements, and the like so made, are punishable by fine or imprisonment, or both, under Section 1001, Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

2/8/05
Date

Signature

Naomi Obinata, Assistant General Counsel
Typed or Printed Name

Assistant General Counsel, Credence Systems Corporation
Title
Registration No.: 39,320

Attorney Docket No.: CRDC-P0363

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent

In re Application of:

Inventor(s): Burnell G. West

Application No.: 10/056,287 Examiner:

Filed: 01/23/02 Art Unit:

For: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT SYSTEM

Patent No.: Issued Date:

CERTIFICATE UNDER 37 CFR 3.73(b)

CREDENCE SYSTEMS, a corporation, certifies that it is the assignee of the entire right, title and interest in the patent application identified above by virtue of either:

[ ] An assignment from the inventor(s) of the patent application identified above. A copy of the assignment is attached.

[X] A chain of title from the inventor(s), of the patent application identified above, to the current assignees as shown below:

1. From: Burnell G. WEST To: Schlumberger Technologies, Inc.
   The document was recorded in the Patent and Trademark Office at Reel:012541, Frame:0016, or for which a copy thereof is attached.

2. From: Schlumberger Technologies, Inc To: NPTest, LLC
   The document was recorded in the Patent and Trademark Office at Reel:014268, Frame:0115, or for which a copy thereof is attached.

3. From: NPTest, LLC To: Credence Systems Corporation
   The document was recorded in the Patent and Trademark Office at Reel:015242, Frame:0574, or for which a copy thereof is attached.

[ ] Additional documents in the chain of title are listed on a supplemental sheet.

[ ] Copies of assignments or other documents in the chain of title are attached.

The undersigned has reviewed all the documents in the chain of title of the patent application identified above and, to the best of undersigned's knowledge and belief, title is in the assignee identified above.

The undersigned (whose title is supplied below) avers that the undersigned is empowered to sign this certificate on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements, and the like so made, are punishable by

fine or imprisonment, or both, under Section 1001, Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

2/8/05
Date

Signature

Naomi Obinata
Typed or Printed Name

Assistant General Counsel/ Intellectual Property
Title

P0363

UNITED STATES DEPARTMENT OF COMMERCE
Patent and Trademark Office
ASSISTANT SECRETARY AND COMMISSIONER
OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

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DENVER, CO 80202-5647

UNITED STATES PATENT AND TRADEMARK OFFICE
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PLEASE REVIEW ALL INFORMATION CONTAINED ON THIS NOTICE. THE INFORMATION CONTAINED ON THIS RECORDATION NOTICE REFLECTS THE DATA PRESENT IN THE PATENT AND TRADEMARK ASSIGNMENT SYSTEM. IF YOU SHOULD FIND ANY ERRORS OR HAVE QUESTIONS CONCERNING THIS NOTICE, YOU MAY CONTACT THE EMPLOYEE WHOSE NAME APPEARS ON THIS NOTICE AT 703-308-9723. PLEASE SEND REQUEST FOR CORRECTION TO: U.S. PATENT AND TRADEMARK OFFICE, ASSIGNMENT DIVISION, BOX ASSIGNMENTS, CG-4, 1213 JEFFERSON DAVIS HWY, SUITE 320, WASHINGTON, D.C. 20231.

RECORDATION DATE: 10/13/2004

REEL/FRAME: 015242/0574
NUMBER OF PAGES: 36

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:
NPTEST, LLC

DOC DATE: 07/13/2004

ASSIGNEE:
CREDENCE SYSTEMS CORPORATION
1421 CALIFORNIA CIRCLE
MILPITAS, CALIFORNIA 95035

SERIAL NUMBER: 09410569
PATENT NUMBER:
TITLE: TEST METHOD FOR SOURCE SYNCHRONOUS SIGNALS

FILING DATE: 10/01/1999
ISSUE DATE:

SERIAL NUMBER: 09628116
PATENT NUMBER:
TITLE: SUPERCONDUCTING SINGLE PHOTON DETECTOR

FILING DATE: 07/28/2000
ISSUE DATE:

CDB

DOCKETED
Date: 12-29-04
Initials: c

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SERIAL NUMBER: 09676292 FILING DATE: 09/28/2000
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD AND APPARATUS FOR REMOTELY TESTING SEMICONDUCTORS

SERIAL NUMBER: 09679042 FILING DATE: 10/02/2000 P0337
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD AND APPARATUS FOR HIGH SPEED IC TEST INTERFACE

SERIAL NUMBER: 09746618 FILING DATE: 12/21/2000
PATENT NUMBER: ISSUE DATE:
TITLE: OPTICAL COUPLING FOR TESTING INTEGRATED CIRCUITS

SERIAL NUMBER: 10056287 FILING DATE: 01/23/2002 P0363
PATENT NUMBER: ISSUE DATE:
TITLE: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT STREAM

SERIAL NUMBER: 10057134 FILING DATE: 01/24/2002 P0364
PATENT NUMBER: ISSUE DATE:
TITLE: COMPARATOR CIRCUIT FOR DIFFERENTIAL SWING COMPARISON AND COMMON-MODE VOLTAGE COMPARISON

SERIAL NUMBER: 10066123 FILING DATE: 01/30/2002
PATENT NUMBER: ISSUE DATE:
TITLE: PICA SYSTEM TIMING MEASUREMENT & CALIBRATION

SERIAL NUMBER: 10079780 FILING DATE: 02/19/2002
PATENT NUMBER: ISSUE DATE:
TITLE: PICA SYSTEM DETECTOR CALIBRATION

SERIAL NUMBER: 10101564 FILING DATE: 03/18/2002
PATENT NUMBER: ISSUE DATE:
TITLE: TEST SYSTEM FORMATTERS

SERIAL NUMBER: 10102526 FILING DATE: 03/19/2002
PATENT NUMBER: ISSUE DATE:
TITLE: TEST SYSTEM ALGORITHMIC PROGRAM GENERATORS

SERIAL NUMBER: 10106280 FILING DATE: 03/25/2002 P0352
PATENT NUMBER: 6794861 ISSUE DATE: 09/21/2004
TITLE: METHOD AND APPARATUS FOR SOCKET CALIBRATION OF INTEGRATED CIRCUIT TESTERS

SERIAL NUMBER: 10136710 FILING DATE: 04/30/2002
PATENT NUMBER: ISSUE DATE:
TITLE: OPEN-LOOP FOR WAVEFORM ACQUISITION

SERIAL NUMBER: 10159527 FILING DATE: 05/30/2002
PATENT NUMBER: ISSUE DATE:
TITLE: SUB-RESOLUTION ALIGNMENT OF IMAGES

SERIAL NUMBER: 10161272 FILING DATE: 05/30/2002
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD AND APPARATUS FOR DETERMINING THICKNESS OF A SEMICONDUCTOR SUBSTRATE AT THE FLOOR OF A TRENCH

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SERIAL NUMBER: 10160606 FILING DATE: 05/30/2002
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD AND APPARATUS FOR FORMING A CAVITY IN A SEMICONDUCTOR SUBSTRATE USING A CHARGED PARTICLE BEAM

SERIAL NUMBER: 10288896 FILING DATE: 11/06/2002
PATENT NUMBER: ISSUE DATE:
TITLE: PRECISE, IN-SITU ENDPOINT DETECTION FOR CHARGED PARTICLE BEAM PROCESSING

SERIAL NUMBER: 10371353 FILING DATE: 02/18/2003
PATENT NUMBER: ISSUE DATE:
TITLE: SIGNAL PATHS PROVIDING MULTIPLE TEST CONFIGURATIONS

SERIAL NUMBER: 10382343 FILING DATE: 03/04/2003 P0318
PATENT NUMBER: 6781218 ISSUE DATE: 08/24/2004
TITLE: METHOD AND APPARATUS FOR ACCESSING INTERNAL NODES OF AN INTEGRATED CIRCUIT USING IC PACKAGE SUBSTRATE

SERIAL NUMBER: 10420675 FILING DATE: 04/21/2003
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD FOR SURFACE PREPARATION TO ENABLE UNIFORM ETCHING OF POLYCRYSTALLINE MATERIALS

SERIAL NUMBER: 10421059 FILING DATE: 04/23/2003
PATENT NUMBER: ISSUE DATE:
TITLE: METHOD FOR BACKSIDE DIE THINNING AND POLISHING OF PACKAGED INTEGRATED CIRCUITS

SERIAL NUMBER: 10678438 FILING DATE: 10/03/2003
PATENT NUMBER: ISSUE DATE:
TITLE: FIB MILLING OF COPPER OVER ORGANIC DIELECTRICS

SERIAL NUMBER: 10466366 FILING DATE: 12/08/2003
PATENT NUMBER: ISSUE DATE:
TITLE: POWER SUPPLY DEVICE FOR A COMPONENT TESTING INSTALLATION

SERIAL NUMBER: 06472427 FILING DATE: 03/07/1983
PATENT NUMBER: 4594544 ISSUE DATE: 06/10/1986
TITLE: PARTICIPATE REGISTER FOR PARALLEL LOADING PIN-ORIENTED REGISTERS IN TEST EQUIPMENT

SERIAL NUMBER: 06611266 FILING DATE: 05/17/1984
PATENT NUMBER: 4651038 ISSUE DATE: 03/17/1987
TITLE: GATE HAVING TEMPERATURE - STABILIZED DELAY

SERIAL NUMBER: 06611454 FILING DATE: 05/17/1984
PATENT NUMBER: 4623802 ISSUE DATE: 11/18/1986
TITLE: MULTIPLE-STAGE GATE NETWORK HAVING INDEPENDENT REFERENCE VOLTAGE SOURCES

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SERIAL NUMBER: 06631958 FILING DATE: 07/18/1984
PATENT NUMBER: 4673917 ISSUE DATE: 06/16/1987
TITLE: METHOD AND APPARATUS FOR MINIMIZING DIGITAL-TO-ANALOG CONVERTER CORRECTION TRIMS

SERIAL NUMBER: 06766905 FILING DATE: 08/16/1985
PATENT NUMBER: 4864228 ISSUE DATE: 09/05/1989
TITLE: ELECTRON BEAM TEST PROBE FOR INTEGRATED CIRCUIT TESTING

SERIAL NUMBER: 06798592 FILING DATE: 11/15/1985
PATENT NUMBER: 4706019 ISSUE DATE: 11/10/1987
TITLE: ELECTRON BEAM TEST PROBE SYSTEM FOR ANALYZING INTEGRATED CIRCUITS

SERIAL NUMBER: 06828157 FILING DATE: 02/10/1986
PATENT NUMBER: 4721909 ISSUE DATE: 01/26/1988
TITLE: APPARATUS FOR PULSING ELECTRON BEAMS

SERIAL NUMBER: 06932762 FILING DATE: 11/19/1986
PATENT NUMBER: 4795984 ISSUE DATE: 01/03/1989
TITLE: MULTI-MARKER, MULTI-DESTINATION TIMING SIGNAL GENERATOR

SERIAL NUMBER: 07196776 FILING DATE: 05/17/1988
PATENT NUMBER: 4912405 ISSUE DATE: 03/27/1990
TITLE: MAGNETIC LENS AND ELECTRON BEAM DEFLECTION SYSTEM

SERIAL NUMBER: 07276359 FILING DATE: 11/23/1988
PATENT NUMBER: 5054097 ISSUE DATE: 10/01/1991
TITLE: METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES

SERIAL NUMBER: 07284775 FILING DATE: 12/12/1988
PATENT NUMBER: 4910698 ISSUE DATE: 03/20/1990
TITLE: A SINE WAVE GENERATOR USING A CORDIC ALOGORITHM

SERIAL NUMBER: 07553202 FILING DATE: 07/13/1990
PATENT NUMBER: 5091693 ISSUE DATE: 02/25/1992
TITLE: DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES

SERIAL NUMBER: 07577986 FILING DATE: 09/05/1990
PATENT NUMBER: 5212443 ISSUE DATE: 05/18/1993
TITLE: EVENT SEQUENCER FOR AUTOMATIC TEST EQUIPMENT

SERIAL NUMBER: 07577987 FILING DATE: 09/05/1990
PATENT NUMBER: 5225772 ISSUE DATE: 07/06/1993
TITLE: AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE

SERIAL NUMBER: 07640636 FILING DATE: 01/14/1991
PATENT NUMBER: 5140164 ISSUE DATE: 08/18/1992
TITLE: IC MODIFICATION WITH FOCUSED ION BEAM SYSTEM

SERIAL NUMBER: 07655255 FILING DATE: 02/13/1991
PATENT NUMBER: 5127064 ISSUE DATE: 06/30/1992
TITLE: HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS

SERIAL NUMBER: 07710768 FILING DATE: 06/04/1991
PATENT NUMBER: 5210487 ISSUE DATE: 05/11/1993
TITLE: DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER

SERIAL NUMBER: 07729510 FILING DATE: 07/12/1991
PATENT NUMBER: 5235273 ISSUE DATE: 08/10/1993
TITLE: APPARATUS FOR SETTING PIN DRIVER/SENSOR REFERENCE VOLTAGE LEVEL

SERIAL NUMBER: 07732351 FILING DATE: 07/17/1991
PATENT NUMBER: 5122988 ISSUE DATE: 06/16/1992
TITLE: DATA STREAM SMOOTHING USING A FIFO MEMORY

SERIAL NUMBER: 07737553 FILING DATE: 07/25/1991
PATENT NUMBER: 5144225 ISSUE DATE: 09/01/1992
TITLE: METHODS AND APPARATUS FOR ACQUIRING DATA FROM INTERMITTENTLY FAILING CIRCUITS

SERIAL NUMBER: 07816639 FILING DATE: 12/30/1991
PATENT NUMBER: 5392222 ISSUE DATE: 02/21/1995
TITLE: LOCATING A FIELD OF VIEW IN WHICH SELECTED IC CONDUCTORS ARE UNOBSCURED

SERIAL NUMBER: 07876566 FILING DATE: 04/30/1992
PATENT NUMBER: 5475624 ISSUE DATE: 12/12/1995
TITLE: TEST GENERATION BY ENVIRONMENT EMULATION

SERIAL NUMBER: 07928919 FILING DATE: 08/12/1992
PATENT NUMBER: 5270643 ISSUE DATE: 12/14/1993
TITLE: PULSED LASER PHOTOEMISSION ELECTRON-BEAM PROBE

SERIAL NUMBER: 07980371 FILING DATE: 11/23/1992
PATENT NUMBER: 5357116 ISSUE DATE: 10/18/1994
TITLE: FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL

SERIAL NUMBER: 08031547 FILING DATE: 03/15/1993
PATENT NUMBER: 5604819 ISSUE DATE: 02/18/1997
TITLE: DETERMINING OFFSET BETWEEN IMAGES OF AN IC

SERIAL NUMBER: 08037507 FILING DATE: 03/24/1993
PATENT NUMBER: 5287022 ISSUE DATE: 02/15/1994
TITLE: METHOD AND CIRCUIT FOR CONTROLLING VOLTAGE REFLECTIONS ON TRANSMISSION LINES

SERIAL NUMBER: 08062362 FILING DATE: 05/13/1993
PATENT NUMBER: 5477139 ISSUE DATE: 12/19/1995
TITLE: EVENT SEQUENCER FOR AUTOMATIC TEST EQUIPMENT

SERIAL NUMBER: 08100975 FILING DATE: 08/03/1993
PATENT NUMBER: 5430400 ISSUE DATE: 07/04/1995
TITLE: DRIVER CIRCUITS FOR IC TESTER

PATENT NUMBER: 5401972 ISSUE DATE: 03/__/1995
TITLE: LAYOUT OVERLAY FOR FIB OPERATIONS

SERIAL NUMBER: 08134330 FILING DATE: 10/12/1993
PATENT NUMBER: 5481550 ISSUE DATE: 01/02/1996
TITLE: APPARATUS FOR MAINTAINING STIMULATION TO A DEVICE UNDER TEST AFTER A TEST STOPS

SERIAL NUMBER: 08228027 FILING DATE: 04/15/1994
PATENT NUMBER: 5530372 ISSUE DATE: 06/25/1996
TITLE: METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT

SERIAL NUMBER: 08267840 FILING DATE: 06/28/1994
PATENT NUMBER: 5461310 ISSUE DATE: 10/24/1995
TITLE: AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE

SERIAL NUMBER: 08268790 FILING DATE: 06/30/1994
PATENT NUMBER: 5616921 ISSUE DATE: 04/01/1997
TITLE: SELF-MASKING FIB MILLING

SERIAL NUMBER: 08434548 FILING DATE: 05/04/1995
PATENT NUMBER: 5700526 ISSUE DATE: 12/23/1997
TITLE: INSULATOR DEPOSITION USING FOCUSED ION BEAM

SERIAL NUMBER: 08488650 FILING DATE: 06/08/1995
PATENT NUMBER: 5638005 ISSUE DATE: 06/10/1997
TITLE: PREDICTIVE WAVEFORM ACQUISITION

SERIAL NUMBER: 08503023 FILING DATE: 07/17/1995
PATENT NUMBER: 5731984 ISSUE DATE: 03/24/1998
TITLE: NECTOR-BASED WAVEFORM ACQUISITION AND DISPLAY

SERIAL NUMBER: 08510397 FILING DATE: 08/01/1995
PATENT NUMBER: 5646521 ISSUE DATE: 07/08/1997
TITLE: ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER

SERIAL NUMBER: 08510395 FILING DATE: 08/01/1995
PATENT NUMBER: 5654657 ISSUE DATE: 08/05/1997
TITLE: ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER

SERIAL NUMBER: 08573071 FILING DATE: 12/15/1995
PATENT NUMBER: 5913022 ISSUE DATE: 06/15/1999
TITLE: LOADING HARDWARE PATTERN MEMORY IN AUTOMATIC TEST EQUIPMENT FOR TESTING CIRCUITS

SERIAL NUMBER: 08626484 FILING DATE: 04/02/1996
PATENT NUMBER: 5675499 ISSUE DATE: 10/07/1997
TITLE: OPTIMAL PROBE POINT PLACEMENT

SERIAL NUMBER: 08696346 FILING DATE: 08/13/1996
PATENT NUMBER: 5673275 ISSUE DATE: 09/30/1997
TITLE: ACCELERATED MODE TESTER TIMING

PATENT NUMBER: 5892949 ISSUE DATE: 04/06/1999
TITLE: ATE TEST PROGRAMMING ARCHITECTURE

SERIAL NUMBER: 08710032 FILING DATE: 09/11/1996
PATENT NUMBER: 5745003 ISSUE DATE: 04/28/1998
TITLE: DRIVER CIRCUITS FOR IC TESTER

SERIAL NUMBER: 08734746 FILING DATE: 10/21/1996
PATENT NUMBER: 5747818 ISSUE DATE: 05/05/1998
TITLE: THERMOELECTRIC COOLING IN GAS-ASSISTED FIB SYSTEM

SERIAL NUMBER: 08734994 FILING DATE: 10/22/1996
PATENT NUMBER: 5918198 ISSUE DATE: 06/29/1999
TITLE: GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER

SERIAL NUMBER: 08745885 FILING DATE: 11/08/1996
PATENT NUMBER: 5959458 ISSUE DATE: 09/28/1999
TITLE: METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY

SERIAL NUMBER: 08756296 FILING DATE: 11/25/1996
PATENT NUMBER: 6078845 ISSUE DATE: 06/20/2000
TITLE: SYSTEM, METHODS AND APPARATUS FOR STORING INFORMATION DURING A SEMICONDUCTOR MANUFACTURING PROCESS

SERIAL NUMBER: 08762395 FILING DATE: 12/09/1996
PATENT NUMBER: 5748124 ISSUE DATE: 05/05/1998
TITLE: ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER

SERIAL NUMBER: 08762611 FILING DATE: 12/09/1996
PATENT NUMBER: 6061815 ISSUE DATE: 05/09/2000
TITLE: PROGRAM UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR

SERIAL NUMBER: 08770621 FILING DATE: 12/19/1996
PATENT NUMBER: 5905266 ISSUE DATE: 05/18/1999
TITLE: CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE

SERIAL NUMBER: 08771804 FILING DATE: 12/20/1996
PATENT NUMBER: 5840630 ISSUE DATE: 11/24/1998
TITLE: FBI ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE

SERIAL NUMBER: 08801687 FILING DATE: 02/18/1997
PATENT NUMBER: 5883905 ISSUE DATE: 03/16/1999
TITLE: PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING

SERIAL NUMBER: 08811104 FILING DATE: 03/03/1997
PATENT NUMBER: 5821549 ISSUE DATE: 10/13/1998
TITLE: THROUGH-THE-SUBSTRATE INVESTIGATION OF FLIP-CHIP IC'S

SERIAL NUMBER: 08818345 FILING DATE: 03/15/1997
PATENT NUMBER: 5905577 ISSUE DATE: 05/18/1999

SERIAL NUMBER: 08841413
PATENT NUMBER: 5920073
TITLE: OPTICAL SYSTEM

FILING DATE: 04/22/1997
ISSUE DATE: 07/06/1999

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SERIAL NUMBER: 08849290 FILING DATE: 05/14/1997
PATENT NUMBER: 6006346 ISSUE DATE: 12/21/1999
TITLE: METHOD AND EQUIPMENT FOR AUTOMATICALLY TESTING ELECTRONIC COMPONENTS

SERIAL NUMBER: 08858992 FILING DATE: 05/20/1997
PATENT NUMBER: 6014764 ISSUE DATE: 01/11/2000
TITLE: PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION

SERIAL NUMBER: 08930501 FILING DATE: 09/30/1997
PATENT NUMBER: 5996099 ISSUE DATE: 11/30/1999
TITLE: METHOD AND APPARATUS FOR AUTOMATICALLY TESTING ELECTRONIC COMPONENTS IN PARALLEL UTILIZING DIFFERENT TIMING SIGNALS FOR EACH ELECTRONIC COMPONENT

SERIAL NUMBER: 08930492 FILING DATE: 09/30/1997
PATENT NUMBER: 6049900 ISSUE DATE: 04/11/2000
TITLE: AUTOMATIC PARALLEL ELECTRONIC COMPONENT TESTING METHOD AND EQUIPMENT

SERIAL NUMBER: 08930490 FILING DATE: 09/30/1997
PATENT NUMBER: 5944846 ISSUE DATE: 08/31/1999
TITLE: METHOD AND APPARATUS FOR SELECTIVELY TESTING INDENTICAL PINS OF A PLURALITY OF ELECTRONIC COMPONENTS

SERIAL NUMBER: 08949747 FILING DATE: 10/14/1997
PATENT NUMBER: 6081484 ISSUE DATE: 06/27/2000
TITLE: MEASURING SIGNALS IN A TESTER SYSTEM

SERIAL NUMBER: 08977649 FILING DATE: 11/24/1997
PATENT NUMBER: 6128754 ISSUE DATE: 10/03/2000
TITLE: TESTER HAVING EVENT GENERATION CIRCUIT FOR ACQUIRING WAVEFORM BY SUPPLYING STROBE EVENTS FOR WAVEFORM ACQUISITION RATHER THAN USING STROBE EVENTS SPECIFIED BY THE TEST PROGRAM

SERIAL NUMBER: 09082455 FILING DATE: 05/20/1998
PATENT NUMBER: 6031229 ISSUE DATE: 02/29/2000
TITLE: AUTOMATIC SEQUENCING OF FIB OPERATIONS

SERIAL NUMBER: 09163710 FILING DATE: 09/30/1998
PATENT NUMBER: 6225626 ISSUE DATE: 05/01/2001
TITLE: THROUGH-THE- SUBSTRATE INVESTIGATION OF FLIP CHIP IC'S

SERIAL NUMBER: 09284939 FILING DATE: 04/22/1999
PATENT NUMBER: 6263464 ISSUE DATE: 07/17/2001
TITLE: DEVICE FOR CONTROLLING CONFORMITY OF CONSUMPTION OF AN ELECTRONIC COMPONENT IN A TESTING MACHINE

SERIAL NUMBER: 09350611 FILING DATE: 07/09/1999
PATENT NUMBER: 6694432 ISSUE DATE: 02/17/2004
TITLE: SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS

SERIAL NUMBER: 09419317 FILING DATE: 10/17/1999
PATENT NUMBER: 6661836 ISSUE DATE: 12/09/2003
TITLE: MEASURING JITTER OF HIGH-SPEED DATA CHANNELS

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SERIAL NUMBER: 09421784 FILING DATE: 10/19/1999
PATENT NUMBER: 6671845 ISSUE DATE: 12/30/2003
TITLE: PACKET-BASED DEVICE TEST SYSTEM

SERIAL NUMBER: 09367376 FILING DATE: 10/25/1999
PATENT NUMBER: 6181117 ISSUE DATE: 01/30/2001
TITLE: POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE

SERIAL NUMBER: 09440985 FILING DATE: 11/16/1999 P0261
PATENT NUMBER: 6410924 ISSUE DATE: 06/25/2002
TITLE: ENERGY FILTERED FOCUSED ION BEAM COLUMN

SERIAL NUMBER: 09452058 FILING DATE: 11/30/1999
PATENT NUMBER: 6285963 ISSUE DATE: 09/04/2001
TITLE: MEASURING SIGNALS IN A TESTER SYSTEM

SERIAL NUMBER: 09483463 FILING DATE: 01/13/2000 P0312
PATENT NUMBER: 6252222 ISSUE DATE: 06/26/2001
TITLE: DIFFERENTIAL PULSED LASER BEAM PROBING OF INTEGRATED CIRCUITS

SERIAL NUMBER: 09500757 FILING DATE: 02/08/2000
PATENT NUMBER: 6496261 ISSUE DATE: 12/17/2002
TITLE: DOUBLE-PULSED OPTICAL INTERFEROMETER FOR WAVEFORM PROBING OF INTEGRATED CIRCUITS

SERIAL NUMBER: 09510101 FILING DATE: 02/22/2000
PATENT NUMBER: 6553522 ISSUE DATE: 04/22/2003
TITLE: VALUATION OF TESTER ACCURACY

SERIAL NUMBER: 09514708 FILING DATE: 02/28/2000 P0302
PATENT NUMBER: 6492797 ISSUE DATE: 12/10/2002
TITLE: SOCKET CALIBRATION METHOD AND APPARATUS

SERIAL NUMBER: 09526979 FILING DATE: 03/15/2000
PATENT NUMBER: 6462814 ISSUE DATE: 10/08/2002
TITLE: BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST

SERIAL NUMBER: 09526407 FILING DATE: 03/15/2000
PATENT NUMBER: 6496953 ISSUE DATE: 12/17/2002
TITLE: CALIBRATION METHOD AND APPARATUS FOR CORRECTING PULSE WIDTH TIMING ERRORS IN INTEGRATED CIRCUIT TESTING

SERIAL NUMBER: 09643576 FILING DATE: 08/22/2000 P0296
PATENT NUMBER: 6501706 ISSUE DATE: 12/31/2002
TITLE: TIME-TO-DIGITAL CONVERTER

SERIAL NUMBER: 09648716 FILING DATE: 08/25/2000 P0297
PATENT NUMBER: 6622107 ISSUE DATE: 09/16/2003
TITLE: EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS

SERIAL NUMBER: 09675090 FILING DATE: 09/28/2000
PATENT NUMBER: 6501288 ISSUE DATE: 12/31/2002
TITLE: ON-CHIP OPTICALLY TRIGGERED LATCH FOR IC TIME MEASUREMENTS

015242/0574 PAGE 10

P0322

SERIAL NUMBER: 09675981 FILING DATE: 09/29/2000
PATENT NUMBER: 6630667 ISSUE DATE: 10/07/2003
TITLE: COMPACT, HIGH COLLECTION EFFICIENCY SCINTILLATOR FOR SECONDARY ELECTRON DETECTION

P0339

SERIAL NUMBER: 09676144 FILING DATE: 09/29/2000
PATENT NUMBER: 6420888 ISSUE DATE: 07/16/2002
TITLE: TEST SYSTEM AND ASSOCIATED INTERFACE MODULE

SERIAL NUMBER: 09696102 FILING DATE: 10/24/2000
PATENT NUMBER: 6748564 ISSUE DATE: 06/08/2004
TITLE: SCAN STREAM SEQUENCING FOR TESTING INTEGRATED CIRCUITS

SERIAL NUMBER: 09781488 FILING DATE: 02/10/2001
PATENT NUMBER: 6518571 ISSUE DATE: 02/11/2003
TITLE: THROUGH-THE-SUBSTRATE INVESTIGATION OF FLIP-CHIP IC'S

SERIAL NUMBER: 09871541 FILING DATE: 05/31/2001
PATENT NUMBER: 6514866 ISSUE DATE: 02/04/2003
TITLE: CHEMICALLY ENHANCED FOCUSED ION BEAM MICRO-MACHINING OF COPPER

SERIAL NUMBER: 09924736 FILING DATE: 08/07/2001
PATENT NUMBER: 6672947 ISSUE DATE: 01/06/2004
TITLE: METHOD FOR GLOBAL DIE THINNING AND POLISHING OF FLIP-CHIP PACKAGED INTEGRATED CIRCUITS

SERIAL NUMBER: 10004018 FILING DATE: 10/18/2001
PATENT NUMBER: 6737853 ISSUE DATE: 05/18/2004
TITLE: PHOTOCONDUCTIVE-SAMPLING VOLTAGE MEASUREMENT

P0339.D10

SERIAL NUMBER: 10132051 FILING DATE: 04/24/2002
PATENT NUMBER: 6522162 ISSUE DATE: 02/18/2003
TITLE: TEST SYSTEM HAVING INTERFACE MODULE

SERIAL NUMBER: 10197134 FILING DATE: 07/16/2002
PATENT NUMBER: 6744267 ISSUE DATE: 06/01/2004
TITLE: TEST SYSTEM AND METHODOLOGY

JEFFREY OLSEN, EXAMINER
ASSIGNMENT DIVISION
OFFICE OF PUBLIC RECORDS

10/15/2004
700122479

Docket No.:

U.S. DEPARTMENT OF COMMERCE
Patent and Trademark Office

PTO-1595 (Modified)
03-01)
No. 0651-0027 (exp.5/31/2002)
REV03

RECORDATION FORM COVER SHEET

PATENTS ONLY

To the Director of the United States Patent and Trademark Office: Please record the attached original documents or copy thereof.

1. Name of conveying party(ies):
NPTest, LLC

Additional names(s) of conveying party(ies) ☐ Yes ☒ No

3. Nature of conveyance:
☒ Assignment
☐ Merger
☐ Security Agreement
☐ Change of Name
☐ Other

Execution Date: July 13, 2004

2. Name and address of receiving party(ies):
Name: Credence Systems Corporation
Address: 1421 California Circle
City: Milpitas State/Prov.: CA
Country: U.S.A. ZIP: 95035
Additional name(s) & address(es) ☐ Yes ☒ No

4. Application number(s) or patent numbers(s):
If this document is being filed together with a new application, the execution date of the application is:

Patent Application No. Filing date
See Attachment A

B. Patent No.(s)
See Attachment A

Additional numbers ☒ Yes ☐ No

5. Name and address of party to whom correspondence concerning document should be mailed:
Name: Gregory P. Durbin, Esq.
Registration No. 42,503
Address: DORSEY & WHITNEY LLP
370 Seventeenth Street, Suite 4700
City: Denver State/Prov.: CO
Country: U.S.A. ZIP: 80202-5647

6. Total number of applications and patents involved: 112

7. Total fee (37 CFR 3.41):....................$ 4,480.00
☐ Enclosed - Any excess or insufficiency should be credited or debited to deposit account
☒ Authorized to be charged to deposit account

8. Deposit account number:
04-1415
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9. Statement and signature.
To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Gregory P. Durbin
Name of Person Signing

Signature

Oct. 12, 2004
Date

Total number of pages including cover sheet, attachments, and documents: 36

Mail documents to be recorded with required cover sheet information to:
Mail Stop Assignment Recordation Services
Director of the United States Patent and Trademark Office
P.O. Box 1450, Alexandria, VA 22313-1450

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No	Grant Date	Patent No	Title	Status	Docket
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers In Test Equipment	Inactive	P0081
United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125
United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
United States	11/13/1988	276,359	10/01/1991	5,054,097	Methods and Apparatus for Alignment of Images	Granted	P0165
United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Setting Pin Driver/Sensor Reference Voltage Level	Granted	P0194
United States	07/17/1991	732,251	08/18/1992	5,140,282	Data Stream Smoothing using a FIFO Memory	Granted	P0170
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192

ATTACHMENT A

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	08/12/1992	07/928,919	12/14/1993	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	10/18/1994	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	02/18/1997	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	02/15/1994	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	12/19/1995	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	07/04/1995	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	03/28/1995	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	01/02/1996	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	06/25/1996	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	10/24/1995	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	04/01/1997	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	12/23/1997	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	06/10/1997	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	03/24/1998	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	07/08/1997	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	08/05/1997	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
United States	12/15/1995	08/573,071	06/15/1999	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	10/07/1997	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	08/13/1996	08/696,346	09/30/1997	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	04/06/1999	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	710,852	04/28/1998	5,745,003	Driver Circuits for IC Tester	Granted	P0245
United States	10/21/1996	08/734,746	05/05/1998	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0252
United States	10/22/1996	08/734,994	06/29/1999	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	

ATTACHMENT A

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244
United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,677	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	09/30/1997	08/930,331	11/30/1999	5,996,099	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0236
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0237
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket No.
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/526,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,716	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337

ATTACHMENT A

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	10/24/2000	09/696,102	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	12/21/2000	09/746,618	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	02/10/2001	09/781,488	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	05/31/2001	09/871,541	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	08/07/2001	09/924,736	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/18/2001	10/004,018	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	01/23/2002	10/056,287	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	01/24/2002	10/057,134	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	01/30/2002	10/066,123	---	---	PICA System Timing Measurement & Calibration	Pending	P0372
United States	02/19/2002	10/079,780	---	---	PICA System Detector Calibration	Pending	P0373
United States	03/18/2002	10/101,564	---	---	Test System Formatters	Pending	P0348
United States	03/19/2002	10/102,526	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	03/25/2002	10/106,280	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	04/24/2002	10/132,051	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	04/30/2002	10/136,710	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	05/30/2002	10/159,527	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	05/30/2002	10/161,272	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	05/30/2002	10/160,606	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	07/16/2002	10/197,134	06/01/2004	6,744,267	Test System and Methodology	Granted	P0370
United States	11/06/2002	10/288,896	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311
United States	02/18/2003	10/371,353	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374

ATTACHMENT A

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338
United States	10/03/2003	10/678,438	---	---	FIB Milling of Copper over Organic Dielectrics	Pending	P0395
United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353

PATENT ASSIGNMENT

WHEREAS, NPTest, LLC, a limited liability company organized and existing under the laws of the State of Delaware, and having its principal place of business at 150 Baytech Drive, San Jose, California 95134, United States of America (the "Assignor"), is the owner of all right, title, and interest in and to the United States and foreign patents and patent applications (the "Patent Rights") listed in Annex A and Annex B hereto; and

WHEREAS, Credence Systems Corporation, a corporation organized and existing under the laws of the State of Delaware, and having its principal place of business at 1421 California Circle, Milpitas, California 95035, United States of America (the "Assignee"), is desirous of acquiring the entire right, title, and interest in and to said Patent Rights;

WHEREAS, Assignor desires to assign and Assignee desires to receive all of Assignor's right, title and interest in and to the Patent Rights;

NOW THEREFORE, for the sum of $1.00 and other good and valuable consideration to it in hand paid, the receipt and sufficiency of which are hereby acknowledged, Assignor has sold, assigned, and set over and by these presents does hereby sell, assign and transfer to the said Assignee, and said Assignee's legal representatives, successors and assigns, any and all of the entire right, title and interest in and to said Patent Rights, any applications, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, or substitutes thereof, all international, foreign and regional applications corresponding thereto, all convention rights corresponding thereto, all priority rights and claims corresponding thereto, and the Letters Patent, both foreign and domestic, that may or shall issue thereon, or any reissues or reexaminations thereof, to be obtained for the Patent Rights;

UPON SAID CONSIDERATION, the Assignor hereby covenants and agrees with the said Assignee that it will not execute any writing or do any act whatsoever conflicting with these presents, and that it will, at any time upon request, without further or additional consideration, but at the expense of the said Assignee, execute such additional assignments and other writings and do such additional acts as said Assignee may deem necessary or desirable to perfect the Assignee's enjoyment of this grant, and render all necessary assistance in making application for and obtaining original, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, reissued, reexamined or extended Letters Patent of the United States, or of any and all foreign countries, on said Patent Rights, and in enforcing any rights or choses in action accruing as a result of such applications or patents, by giving testimony in any proceedings or transactions involving such applications or patents, and by executing preliminary statements and other affidavits, it being understood that the foregoing covenant and agreement shall bind, and inure to the benefit of, the assigns and legal representatives of both parties.

IN WITNESS WHEREOF, the Assignor has executed this Assignment and caused the same to be duly delivered on its behalf on the day and year first set forth below.

NPTEST, LLC

July 12, 2004
Date

By: Leslie Weise
Name: Leslie Weise
Title: General Counsel and Secretary

STATE OF CALIFORNIA)
) ss.
COUNTY OF SANTA CLARA)

On this 12 day of July, 2004, before me a Notary Public, personally appeared Leslie Weise, the above-mentioned representative of the Assignor, NPTest, LLC, who executed the foregoing Assignment, and represented and acknowledged that he/she had the requisite corporate authority to execute this Assignment and the same was executed as a free act and deed.

SHELLY M. GARRETT
Commission # 1426539
Notary Public - California
Santa Clara County
My Comm. Expires Jul 17, 2007

Notary Public

My commission expires: July 17, 2007.

IN WITNESS WHEREOF, Assignee confirms the acceptance of the assignment of the Patent Rights from the Assignor.

CREDENCE SYSTEMS CORPORATION

7/13/04
Date

By:
Name: Byron Milstead
Title: Vice President and General Counsel

STATE OF CALIFORNIA)
) ss.
COUNTY OF SANTA CLARA)

On this 13 day of July, 2004, before me a Notary Public, personally appeared Byron Milstead, the above-mentioned representative of the Assignee, Credence Systems Corporation, who executed the foregoing Patent Assignment, and represented

and acknowledged that he/she had the requisite corporate authority to execute and accept this Patent Assignment and the same was executed as a free act and deed.

(S E A L)

Notary Public

My commission expires: July 17, 2007.

SHELLY M. GARRETT
Commission # 1426539
Notary Public - California
Santa Clara County
My Comm. Expires Jul 17, 2007

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO [redacted]

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers In Test Equipment	Inactive	P0081
REDACTED							
United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125
REDACTED							
United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
United States	11/13/1988	276,359	10/01/1991	5,054,097	Methods and Apparatus for Alignment of Images	Granted	P0165
United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Setting Pin Driver/Sensor Reference Voltage Level	Granted	P0194

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	07/17/1991	732,351	06/16/1992	5,122,988	Data Stream Smoothing using a FIFO Memory	Granted	P0172
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192
United States	08/12/1992	07/928,919	12/14/1993	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	10/18/1994	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	02/18/1997	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	02/15/1994	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	12/19/1995	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	07/04/1995	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	03/28/1995	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	01/02/1996	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	06/25/1996	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	10/24/1995	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	04/01/1997	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	12/23/1997	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	06/10/1997	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	03/24/1998	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	07/08/1997	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	08/05/1997	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
REDACTED							
United States	12/15/1995	08/573,071	06/15/1999	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	10/07/1997	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	08/13/1996	08/696,346	09/30/1997	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	04/06/1999	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	710,032	04/28/1998	5,745,003	Driver Circuits for IC Tester	Granted	P0243
United States	10/21/1996	08/734,746	05/05/1998	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0245
United States	10/22/1996	08/734,994	06/29/1999	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	P0252
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244

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United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,577	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	09/30/1997	08/930,501	11/30/1999	5,996,099	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0236
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0237

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Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/526,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,716	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scinitillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337
United States	10/24/2000	09/696,102	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	12/21/2000	09/746,618	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	02/10/2001	09/781,488	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246

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United States	05/31/2001	09/871,541	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	08/07/2001	09/924,736	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/18/2001	10/004,018	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	01/23/2002	10/056,287	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	01/24/2002	10/057,134	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	01/30/2002	10/066,123	---	---	PICA System Timing Measurement & Calibration	Pending	P0372
United States	02/19/2002	10/079,780	---	---	PICA System Detector Calibration	Pending	P0373
United States	03/18/2002	10/101,564	---	---	Test System Formatters	Pending	P0348

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/19/2002	10/102,526	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	03/25/2002	10/106,280	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	04/24/2002	10/132,051	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	04/30/2002	10/136,710	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	05/30/2002	10/159,527	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	05/30/2002	10/161,272	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	05/30/2002	10/160,606	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	07/16/2002	10/197,134	06/01/2004	6,744,267	Test System and Methodology	Granted	P0370

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Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	11/06/2002	10/288,896	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311

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United States	02/18/2003	10/371,353	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374
United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338

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Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	10/03/2003	10/678,438	---	---	FIB Milling of Copper over Organic Dielectrics	Pending	P0395

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United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353

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UNITED STATES PATENT AND TRADEMARK OFFICE

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JANUARY 21, 2004

PTAS

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RECORDATION DATE: 06/23/2003

REEL/FRAME: 014268/0115
NUMBER OF PAGES: 28

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:
SCHLUMBERGER TECHNOLOGIES, INC.

DOC DATE: 05/10/2002

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SERIAL NUMBER: 09350611
PATENT NUMBER:

FILING DATE: 07/09/1999
ISSUE DATE:

SERIAL NUMBER: 09410569
PATENT NUMBER:

FILING DATE: 10/01/1999
ISSUE DATE:

SERIAL NUMBER: 09419317
PATENT NUMBER: 6661836

FILING DATE: 10/17/1999
ISSUE DATE: 12/09/2003

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SERIAL NUMBER: 09421784 PATENT NUMBER: 6671845	FILING DATE: 10/19/1999 ISSUE DATE: 12/30/2003
SERIAL NUMBER: 09628116 PATENT NUMBER:	FILING DATE: 07/28/2000 ISSUE DATE:
SERIAL NUMBER: 09648716 PATENT NUMBER: 6622107	FILING DATE: 08/25/2000 ISSUE DATE: 09/16/2003
SERIAL NUMBER: 09676292 PATENT NUMBER:	FILING DATE: 09/28/2000 ISSUE DATE:
SERIAL NUMBER: 09675981 PATENT NUMBER: 6630667	FILING DATE: 09/29/2000 ISSUE DATE: 10/07/2003
SERIAL NUMBER: 09679042 PATENT NUMBER:	FILING DATE: 10/02/2000 ISSUE DATE:
SERIAL NUMBER: 09696102 PATENT NUMBER:	FILING DATE: 10/24/2000 ISSUE DATE:
SERIAL NUMBER: 09746618 PATENT NUMBER:	FILING DATE: 12/21/2000 ISSUE DATE:
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SERIAL NUMBER: 10057134 PATENT NUMBER:	FILING DATE: 01/24/2002 ISSUE DATE:
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SERIAL NUMBER: 10101564 PATENT NUMBER:	FILING DATE: 03/18/2002 ISSUE DATE:
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SERIAL NUMBER: 10123842 PATENT NUMBER:	FILING DATE: 04/15/2002 ISSUE DATE:

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SERIAL NUMBER: 10136710 PATENT NUMBER:	FILING DATE: 04/30/2002 ISSUE DATE:
SERIAL NUMBER: 06472427 PATENT NUMBER: 4594544	FILING DATE: 03/07/1983 ISSUE DATE: 06/10/1986
SERIAL NUMBER: 06611454 PATENT NUMBER: 4623802	FILING DATE: 05/17/1984 ISSUE DATE: 11/18/1986
SERIAL NUMBER: 06611266 PATENT NUMBER: 4651038	FILING DATE: 05/17/1984 ISSUE DATE: 03/17/1987
SERIAL NUMBER: 06631958 PATENT NUMBER: 4673917	FILING DATE: 07/18/1984 ISSUE DATE: 06/16/1987
SERIAL NUMBER: 06798592 PATENT NUMBER: 4706019	FILING DATE: 11/15/1985 ISSUE DATE: 11/10/1987
SERIAL NUMBER: 06828157 PATENT NUMBER: 4721909	FILING DATE: 02/10/1986 ISSUE DATE: 01/26/1988
SERIAL NUMBER: 06932762 PATENT NUMBER: 4795984	FILING DATE: 11/19/1986 ISSUE DATE: 01/03/1989
SERIAL NUMBER: 06766905 PATENT NUMBER: 4864228	FILING DATE: 08/16/1985 ISSUE DATE: 09/05/1989
SERIAL NUMBER: 07284775 PATENT NUMBER: 4910698	FILING DATE: 12/12/1988 ISSUE DATE: 03/20/1990
SERIAL NUMBER: 07196776 PATENT NUMBER: 4912405	FILING DATE: 05/17/1988 ISSUE DATE: 03/27/1990
SERIAL NUMBER: 07276359 PATENT NUMBER: 5054097	FILING DATE: 11/23/1988 ISSUE DATE: 10/01/1991
SERIAL NUMBER: 07553202 PATENT NUMBER: 5091693	FILING DATE: 07/13/1990 ISSUE DATE: 02/25/1992
SERIAL NUMBER: 07732351 PATENT NUMBER: 5122988	FILING DATE: 07/17/1991 ISSUE DATE: 06/16/1992
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SERIAL NUMBER: 07737553 PATENT NUMBER: 5144225	FILING DATE: 07/25/1991 ISSUE DATE: 09/01/1992

SERIAL NUMBER: 07710768 PATENT NUMBER: 5210487	FILING DATE: 06/04/1991 ISSUE DATE: 05/11/1993
SERIAL NUMBER: 07577986 PATENT NUMBER: 5212443	FILING DATE: 09/05/1990 ISSUE DATE: 05/18/1993
SERIAL NUMBER: 07577987 PATENT NUMBER: 5225772	FILING DATE: 09/05/1990 ISSUE DATE: 07/06/1993
SERIAL NUMBER: 07729510 PATENT NUMBER: 5235273	FILING DATE: 07/12/1991 ISSUE DATE: 08/10/1993
SERIAL NUMBER: 07928919 PATENT NUMBER: 5270643	FILING DATE: 08/12/1992 ISSUE DATE: 12/14/1993
SERIAL NUMBER: 08037507 PATENT NUMBER: 5287022	FILING DATE: 03/24/1993 ISSUE DATE: 02/15/1994
SERIAL NUMBER: 07980371 PATENT NUMBER: 5357116	FILING DATE: 11/23/1992 ISSUE DATE: 10/18/1994
SERIAL NUMBER: 07816639 PATENT NUMBER: 5392222	FILING DATE: 12/30/1991 ISSUE DATE: 02/21/1995
SERIAL NUMBER: 08115997 PATENT NUMBER: 5401972	FILING DATE: 09/02/1993 ISSUE DATE: 03/28/1995
SERIAL NUMBER: 08100975 PATENT NUMBER: 5430400	FILING DATE: 08/03/1993 ISSUE DATE: 07/04/1995
SERIAL NUMBER: 08267840 PATENT NUMBER: 5461310	FILING DATE: 06/28/1994 ISSUE DATE: 10/24/1995
SERIAL NUMBER: 07876566 PATENT NUMBER: 5475624	FILING DATE: 04/30/1992 ISSUE DATE: 12/12/1995
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SERIAL NUMBER: 08228027 PATENT NUMBER: 5530372	FILING DATE: 04/15/1994 ISSUE DATE: 06/25/1996
SERIAL NUMBER: 08031547 PATENT NUMBER: 5604819	FILING DATE: 03/15/1993 ISSUE DATE: 02/18/1997
SERIAL NUMBER: 08268790 PATENT NUMBER: 5616921	FILING DATE: 06/30/1994 ISSUE DATE: 04/01/1997
SERIAL NUMBER: 08488650 PATENT NUMBER: 5638005	FILING DATE: 06/08/1995 ISSUE DATE: 06/10/1997

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SERIAL NUMBER: 08510397 FILING DATE: 08/01/1995
PATENT NUMBER: 5646521 ISSUE DATE: 07/08/1997

SERIAL NUMBER: 08510395 FILING DATE: 08/01/1995
PATENT NUMBER: 5654657 ISSUE DATE: 08/05/1997

SERIAL NUMBER: 08696346 FILING DATE: 08/13/1996
PATENT NUMBER: 5673275 ISSUE DATE: 09/30/1997

SERIAL NUMBER: 08626484 FILING DATE: 04/02/1996
PATENT NUMBER: 5675499 ISSUE DATE: 10/07/1997

SERIAL NUMBER: 08434548 FILING DATE: 05/04/1995
PATENT NUMBER: 5700526 ISSUE DATE: 12/23/1997

SERIAL NUMBER: 08503023 FILING DATE: 07/17/1995
PATENT NUMBER: 5731984 ISSUE DATE: 03/24/1998

SERIAL NUMBER: 08710032 FILING DATE: 09/11/1996
PATENT NUMBER: 5745003 ISSUE DATE: 04/28/1998

SERIAL NUMBER: 08734746 FILING DATE: 10/21/1996
PATENT NUMBER: 5747818 ISSUE DATE: 05/05/1998

SERIAL NUMBER: 08762395 FILING DATE: 12/09/1996
PATENT NUMBER: 5748124 ISSUE DATE: 05/05/1998

SERIAL NUMBER: 08811104 FILING DATE: 03/03/1997
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PATENT NUMBER: 5883905 ISSUE DATE: 03/16/1999

SERIAL NUMBER: 08705795 FILING DATE: 08/30/1996
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SERIAL NUMBER: 08770621 FILING DATE: 12/19/1996
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PATENT NUMBER: 5905577 ISSUE DATE: 05/18/1999

SERIAL NUMBER: 08573071 FILING DATE: 12/15/1995
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SERIAL NUMBER: 08841413 FILING DATE: 04/22/1997
PATENT NUMBER: 5920073 ISSUE DATE: 07/06/1999

SERIAL NUMBER: 08930490 PATENT NUMBER: 5944846	FILING DATE: 09/30/1997 ISSUE DATE: 08/31/1999
SERIAL NUMBER: 08745885 PATENT NUMBER: 5959458	FILING DATE: 11/08/1996 ISSUE DATE: 09/28/1999
SERIAL NUMBER: 08930501 PATENT NUMBER: 5996099	FILING DATE: 09/30/1997 ISSUE DATE: 11/30/1999
SERIAL NUMBER: 08849290 PATENT NUMBER: 6006346	FILING DATE: 05/14/1997 ISSUE DATE: 12/21/1999
SERIAL NUMBER: 08858992 PATENT NUMBER: 6014764	FILING DATE: 05/20/1997 ISSUE DATE: 01/11/2000
SERIAL NUMBER: 09082455 PATENT NUMBER: 6031229	FILING DATE: 05/20/1998 ISSUE DATE: 02/29/2000
SERIAL NUMBER: 08930492 PATENT NUMBER: 6049900	FILING DATE: 09/30/1997 ISSUE DATE: 04/11/2000
SERIAL NUMBER: 08762611 PATENT NUMBER: 6061815	FILING DATE: 12/09/1996 ISSUE DATE: 05/09/2000
SERIAL NUMBER: 08756296 PATENT NUMBER: 6078845	FILING DATE: 11/25/1996 ISSUE DATE: 06/20/2000
SERIAL NUMBER: 08949747 PATENT NUMBER: 6081484	FILING DATE: 10/14/1997 ISSUE DATE: 06/27/2000
SERIAL NUMBER: 08977649 PATENT NUMBER: 6128754	FILING DATE: 11/24/1997 ISSUE DATE: 10/03/2000
SERIAL NUMBER: 09367376 PATENT NUMBER: 6181117	FILING DATE: 10/25/1999 ISSUE DATE: 01/30/2001
SERIAL NUMBER: 09163710 PATENT NUMBER: 6225626	FILING DATE: 09/30/1998 ISSUE DATE: 05/01/2001
SERIAL NUMBER: 09483463 PATENT NUMBER: 6252222	FILING DATE: 01/13/2000 ISSUE DATE: 06/26/2001
SERIAL NUMBER: 09284939 PATENT NUMBER: 6263464	FILING DATE: 04/22/1999 ISSUE DATE: 07/17/2001
SERIAL NUMBER: 09452058 PATENT NUMBER: 6285963	FILING DATE: 11/30/1999 ISSUE DATE: 09/04/2001
SERIAL NUMBER: 09440985 PATENT NUMBER: 6410924	FILING DATE: 11/16/1999 ISSUE DATE: 06/25/2002
SERIAL NUMBER: 09676144 PATENT NUMBER: 6420888	FILING DATE: 09/29/2000 ISSUE DATE: 07/16/2002

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SERIAL NUMBER: 09514708 PATENT NUMBER: 6492797	FILING DATE: 02/28/2000 ISSUE DATE: 12/10/2002
SERIAL NUMBER: 09500757 PATENT NUMBER: 6496261	FILING DATE: 02/08/2000 ISSUE DATE: 12/17/2002
SERIAL NUMBER: 09526407 PATENT NUMBER: 6496953	FILING DATE: 03/15/2000 ISSUE DATE: 12/17/2002
SERIAL NUMBER: 09643576 PATENT NUMBER: 6501706	FILING DATE: 08/22/2000 ISSUE DATE: 12/31/2002
SERIAL NUMBER: 09675090 PATENT NUMBER: 6501288	FILING DATE: 09/28/2000 ISSUE DATE: 12/31/2002
SERIAL NUMBER: 09871541 PATENT NUMBER: 6514866	FILING DATE: 05/31/2001 ISSUE DATE: 02/04/2003
SERIAL NUMBER: 09781488 PATENT NUMBER: 6518571	FILING DATE: 02/10/2001 ISSUE DATE: 02/11/2003
SERIAL NUMBER: 10132051 PATENT NUMBER: 6522162	FILING DATE: 04/24/2002 ISSUE DATE: 02/18/2003
SERIAL NUMBER: 09510101 PATENT NUMBER: 6553522	FILING DATE: 02/22/2000 ISSUE DATE: 04/22/2003

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SKJERVEN, MORRILL, MACPHERSON, L.L.P.

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PLEASE REVIEW ALL INFORMATION CONTAINED ON THIS NOTICE. THE INFORMATION CONTAINED ON THIS RECORDATION NOTICE REFLECTS THE DATA PRESENT IN THE PATENT AND TRADEMARK ASSIGNMENT SYSTEM. IF YOU SHOULD FIND ANY ERRORS OR HAVE QUESTIONS CONCERNING THIS NOTICE, YOU MAY CONTACT THE EMPLOYEE WHOSE NAME APPEARS ON THIS NOTICE AT 703-308-9723. PLEASE SEND REQUEST FOR CORRECTION TO: U.S. PATENT AND TRADEMARK OFFICE, ASSIGNMENT DIVISION, BOX ASSIGNMENTS, CG-4, 1213 JEFFERSON DAVIS HWY, SUITE 320, WASHINGTON, D.C. 20231.

RECORDATION DATE: 01/23/2002

REEL/FRAME: 012541/0016
NUMBER OF PAGES: 2

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:
WEST, BURNELL G.

DOC DATE: 01/21/2002

ASSIGNEE:
SCHLUMBERGER TECHNOLOGIES, INC.
150 BAYTECH DRIVE
SAN JOSE, CALIFORNIA 95134-2302

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SERIAL NUMBER: 10056287
PATENT NUMBER:

FILING DATE: 01/23/2002
ISSUE DATE:

PAULA MCCRAY, EXAMINER
ASSIGNMENT DIVISION
OFFICE OF PUBLIC RECORDS

ATTORNEY: NRK M-12401 US
Assignment F/U removed
ACTION: _____ DUE: _____
ACTION: _____ DUE: _____
ACTION: _____ DUE: _____
DOCKETED BY: _____ DATE: 7-18-02
FORM LETTER: YES / NO

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DOCKETED
Date: 2-3-01
Initials: _____

07739 NPTest, Inc.
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U.S. DEPARTMENT OF COMMERCE
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TO THE HONORABLE DIRECTOR OF THE UNITED STATES PATENT AND TRADEMARK OFFICE. PLEASE RECORD THE ATTACHED ORIGINAL DOCUMENTS OR COPY THEREOF.

1. Name of conveying party(ies):

(a) Burnell G. West 1/23/02

Additional name(s) of conveying party(ies) attached?

☐ Yes ☒ No

2. Name and address of receiving party(ies):

Name: SCHLUMBERGER TECHNOLOGIES, INC.

Street Address: 150 Baytech Drive

City: San Jose California 95134-2302

Country: United States

3. Nature of Conveyance:

☒ Assignment ☐ Merger

☐ Security Agreement ☐ Change of Name

☐ Other _____

Execution Date: January 21, 2002

Additional name(s) & address(es) attached?

☐ Yes ☒ No

J1050 U.S. PTO 10/056287 01/23/02

4. Application number(s) or patent number(s):

If this document is being filed together with a new application, the execution date of the application is: January 21, 2002

A. Patent Application No.(s) -

Title: **CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT STREAM**

B. Patent No.(s) 10/056287

Additional numbers attached? ☐ Yes ☒ No

5. Name and address of party to whom correspondence concerning document should be mailed:

Name: Todd M. Briggs

Internal Address: SKJERVEN MORRILL MacPHERSON LLP

Street Address: 3 EMBARCADERO CENTER, SUITE 2800

City SAN FRANCISCO State CA Zip 94111

6. Total number of applications and patents involved: One

7. Total fee (37 CFR 3.41): $40.00

☒ Authorized to be charged to Deposit Account 19-2386

☒ Charge Deposit Account 19-2386 for any additional fees required for this conveyance and credit deposit account 19-2386 any amounts overpaid

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8. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Todd M. Briggs 44,040
Name of Person Signing

Todd M Briggs
Signature

1-23-02
Date

Total number of pages including cover sheet, attachments, and documents: Two

Attorney Docket No.: M-12401 US

ASSIGNMENT

For good and valuable consideration, receipt of which is hereby acknowledged, I, Burnell G. West of Fremont, California, hereby sell, assign and transfer to **SCHLUMBERGER TECHNOLOGIES, INC.**, a Delaware corporation, having a place of business at 150 Baytech Drive, San Jose, California 95134-2302, its successors and assigns, the entire right, title and interest throughout the world in my invention in

CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT STREAM

for which I have executed a United States patent application on or about the date of this assignment, and all patent applications and patents of every country for said invention, including divisions, reissues, continuations and extensions thereof, and all rights of priority resulting from the filing of said applications; I authorize the above-named assignee to apply for patents of foreign countries for said invention, and to claim all rights of priority without further authorization from me; I agree to execute all papers useful in connection with said United States and foreign applications, and generally to do everything possible to aid said assignee, its successors, assigns and nominees, at their request and expense, in obtaining and enforcing patents for said invention in all countries; and I request the Commissioner of Patents and Trademarks to issue all patents granted for said invention to the above-named assignee, its successors and assigns.

Executed this 21 day of January, 2002.

Burnell G. West

State of California)
) ss
County of Santa Clara)

On January 21, 2002 before me, Leticia G. Rosenthal, Notary Public, personally appeared Burnell G. West personally known to me or proved to me on the basis of satisfactory evidence to be the person(~~s~~) whose name(~~s~~) is(~~are~~) subscribed to the within instrument and acknowledged to me that he/~~she~~/~~they~~ executed the same in his/~~her~~/~~their~~ authorized capacity(~~ies~~), and that by his/~~her~~/~~their~~ signature(~~s~~) on the instrument the person(~~s~~), or the entity upon behalf of which the person(~~s~~) acted, executed the instrument.

WITNESS my hand and official seal.

Leticia G. Rosenthal
SIGNATURE OF NOTARY

LETICIA G. ROSENTHAL
Commission # 1275798
Notary Public - California
Santa Clara County
My Comm. Expires Sep 2, 2004